Contribution ID: **16** Type: **not specified**

Large Area Inspection and Metrology for High Performance Integrated Structure

Wednesday 2 July 2014 11:00 (30 minutes)

A variety of new tools and methods have become available which provide fast and accurate metrological data in an efficient and scalable way. These include high speed line scanners, laser, and confocal surface probes.

We will report on studies made, using these methods, of
1) precision metrology of large electro-mechanical co-cured laminates
2) non-contact imaging of hidden defects in precision laminates
3) development of scalable inspection systems which would be appropriate for fabrication workflow in the HL-LHC detector assembly process.

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